Amrita Vishwa Vidyapeetham

Amrita School of Engineering, Coimbatore

Department of Electronics and Communication Engineering

1. Course Code: 25VL601

2. Course Title: Semiconductor Device Modelling

3. Course Type (Core Course/Elective): Core

4. Course Mentor: Dr. Abhishek Raj

5. Course Instructor(s): Dr. Abhishek Raj

6. **Academic year:** 2025 – 2026 Odd

7. Course Objectives and Course Summary:

Learning Objectives:

- Understand semiconductor fundamentals, pn junctions, and MOS structure behavior.
- Analyze two- and three-terminal MOS devices, focusing on inversion and capacitance.
- Model four-terminal MOS transistors across operating regions with practical effects.
- Study short-channel effects, develop large-signal and non-quasi-static models, and gain an overview of modern semiconductor devices.

Course Summary:

Students will understand MOS transistor operation, analyze scaling effects, apply modeling techniques for circuit simulation, and optimize VLSI designs.

8. Course Outcomes (COs):

CO1: explain the physical behavior of intrinsic and extrinsic semiconductors, pn junctions, and MOS structures under various biasing conditions.

CO2: analyze the characteristics of two- and three-terminal MOS devices and interpret the effects of gate voltage on device behavior.

CO3: model four-terminal MOS transistors considering different regions of operation, mobility variations, and temperature effects.

CO4: evaluate short-channel effects and develop models for scaled MOS devices, with an overview of advanced structures including SOI, Double Gate, FinFET, and GAA-FETs.

9. Mapping/Alignment of COs with Program Outcomes (POs):

CO/PO	PO 1	PO 2	PO 3	PO 4	PO 5	PO6
CO 1	-	-	-	3	-	-
CO 2	-	-	-	3	2	-
CO 3	-	-	-	3	3	2
CO 4	-	-	-	3	3	2

- 10. Comments from previous course offering: NA
- 11. Reflection by the current course instructor(s): Mathematical modelling of MOS transistor to be focused.

12. Class Schedule/Lesson Plan/Weekly plan

Topics	Lecture(s)	Specific Outcome	Teaching Strategies & Suggested Activities	Teaching Reading Materials	Assessment Technique	Alignment to COs
Basics of Semiconduct or – Intrinsic and Extrinsic Semiconduct ors, Equilibrium in absence and presence of Electric Field	1-2	Understand carrier concentrations in intrinsic/extrinsic semiconductors and explain equilibrium behavior under applied electric fields.	Class Room Teaching - Power Point, Chalk and Talk	Chapter 1 (Text book 1)	Midterm Exam, End sem Exam	COI
Non- Equilibrium and Quasi- Fermi Levels, Charge Density, Electric Field, Potential, Poisson's Equation	3 - 6	Analyze non-equilibrium carrier distributions using quasi-Fermi levels and solve Poisson's equation to determine electric potential profiles.	Class Room Teaching - Power Point, Chalk and Talk	Chapter 1 (Text book 1)	Midterm Exam, End sem Exam	CO1
Transit Time, Drift and Diffusion current, Contact Potentials, The pn Junction	7-9	Calculate carrier transport parameters and describe the I-V characteristics and built-in potential of a pn junction.	Class Room Teaching - Power Point, Chalk and Talk	Chapter 1 (Text book 1)	Midterm Exam, End Sem Exam	CO1
Overview of the MOS Transistor – Structure, Operation and Characteristi cs of MOS Transistor.	10-11	Illustrate MOS transistor structure and explain its basic operation in cutoff, linear, and saturation regions.	Class Room Teaching - Power Point, Chalk and Talk	Chapter 1 (Text book 1)	Quiz, Midterm Exam, End Sem Exam	CO1
			Quiz-I			

The Two- Terminal MOS Structures – Flatband Voltage, Potential Balance and Charge Balance, Effect of Gate-Body Voltage on Surface Condition	12-13	Evaluate surface conditions for two-terminal MOS structures under varying gate voltages.	Class Room Teaching - Power Point, Chalk and Talk	Chapter 2 (Text book 1)	Midterm Exam, End Sem Exam	CO1, CO3
Accumulatio n and Depletion, Inversion, Small-Signal Capacitance	14-15	Evaluate small-signal capacitance for two-terminal MOS structures under varying gate voltages.	Class Room Teaching - Power Point, Chalk and Talk Quiz-II	Chapter 2 (Text book 1)	Quiz, Midterm Exam, End Sem Exam	CO1, CO3
The Three-Terminal MOS Structure – Contacting the Inversion Layer, The Body Effect, Regions of Inversion, A "V _{CB} Control" Point of View, Uses for Three-Terminal MOS Structures.	16-20	Understand body effect and control mechanisms in three-terminal MOS devices and identify practical use cases.	Class Room Teaching - Power Point, Chalk and Talk	Chapter 3 (Text book 1)	Midterm Exam, End Sem Exam	CO1, CO3
	T		Term Examinat			
The Four- Terminal MOS Transistor - Transistor Regions of Operation, Complete All-Region Model, Simplified All-Region	21-25	Model MOSFET operation across all regions using various compact models and quasi-Fermibased approaches.	Class Room Teaching - Power Point, Chalk and Talk	Chapter 4 (Text book 1)	End Sem Exam	CO1, CO3

Models,						
Models						
Based on						
Quasi-Fermi						
Potentials,						
Regions of						
Inversion in						
Terms of						
Terminal						
Voltages,						
Strong						
Inversion,						
Weak						
Inversion,						
Moderate-						
Inversion						
and Single-						
Piece Models						
	26.20	Comm	Class	Clarat 4	D. 1	CO1 CO2
Source-	26-30	Compare	Class	Chapter 4	End	CO1, CO3
Referenced		modeling	Room	(Text	Sem Exam	
vs. Body-		approaches,	Teaching -	book 1)		
Referenced		analyze mobility	Power			
Modeling,		and resistance	Point, Chalk			
Effective		effects, and	and			
Mobility,		evaluate model	Talk			
Effect of		accuracy for				
Extrinsic		different				
Source and		transistor types.				
Drain Series		in an analysis of the same of				
Resistances,						
Temperature						
Effects,						
Breakdown,						
The p-						
Channel						
MOS						
Transistor,						
Enhancemen						
t-Mode and						
Depletion-						
Mode						
Transistors,						
Model						
Parameter						
Values,						
Model						
Accuracy,						
and Model						
Comparison.	2.2.	71 10 1	C1		0 :	GOS
Small-	31-34	Identify and	Class	Chapter 5	Quiz, End	CO2
Dimension		quantify short-	Room	(Text	Sem Exam	
Effects -		channel effects	Teaching -	book 1)		
Carrier		and incorporate	Power			
Velocity		them into unified	Point, Chalk			
Saturation,		MOSFET models	and			
,		1.10 21 21 models		I	l	l

Channel Length			Talk			
Modulation, Charge						
Sharing,						
Drain-						
Induced						
Barrier Lowering,						
Punchthroug						
h,						
Combining						
Several Small-						
Dimension						
Effects into						
One Model						
			Quiz-III			
Hot Carrier	35-39	Evaluate	Class	Chapter 5	Assignment,	CO2
Effects and		advanced device	Room	(Text	End Sem	
Impact Ionization,		phenomena and scaling	Teaching - Power	book 1)	Exam	
Velocity		challenges	Point, Chalk			
Overshoot		including	and			
and Ballistic		leakage, ballistic	Talk			
Operation, Polysilicon		transport, and quantum effects.				
Depletion,		quantum criccis.				
Quantum						
Mechanical						
Effects, DC Gate						
Current,						
Junction						
Leakage,						
Band-to-						
Band Tunneling						
and GIDL,						
Leakage						
Currents—						
Particular Cases, The						
Quest for						
Ever-Smaller						
Devices.						
			Assignment-I		T	
Large-Signal	40-43	Develop and	Class	Chapter 6	End Sem	CO1, CO3,
Modeling of MOS		analyze large- signal MOS	Room Teaching -	(Text book 1)	Exam	CO4
Transistor -		models	Power	000K 1)		
Quasi-Static		considering	Point, Chalk			
Operation,		intrinsic/extrinsic	and			

Terminal		parasitics and	Talk			
Currents in		non-quasi-static	Tunk			
Quasi-Static		behavior.				
Operation,						
Evaluation of						
Intrinsic						
Charges in						
Quasi-Static						
Operation,						
Transit Time						
under DC						
Conditions,						
Limitations						
of the Quasi-						
Static Model,						
Non-Quasi-						
Static						
Modeling,						
Extrinsic						
Parasitics.						
Overview of	43-45	Develop and	Class	Text Book 4	End Sem	CO4
Modern	43-43	analyze large-	Room	Text Book 4	Exam	CO4
Semiconductor		signal MOS	Teaching -		Lxam	
Devices – SOI		models	Power			
MOSFETs,		considering	Point, Chalk			
Multi-gate Gate		intrinsic/extrinsic	and			
FETs like -		parasitics and	Talk			
Double Gate,		non-quasi-static	Tuik			
FinFET, Gate		behavior.				
All Around		001141101.				
FETs (GAA-						
FETs).						

Reference(s)

- 1. Y. Tsividis and C. McAndrew, "Operation and Modeling of the MOS Transistor", Oxford University Press, 2011.
- 2. **Donald Neamen, Dhrubes Biswas**, "Semiconductor Physics and Devices", McGraw Hill, 2017.
- 3. **Jerry Fossum and Vishal Trivedi**, "Fundamentals of Ultra thin body MOSFETs and FinFETs", Cambridge University Press, 2013
- 4. Jean-Pierre Colinge "FinFETs and other Multi Gate Transistors", Springer (2008).
- 5. Samar K. Saha, "Compact Models for Integrated Circuit Design Conventional Transistors and Beyond", CRC Press (Taylor & Francis), 2016.
- 13. Teaching-Learning Strategies Class Room Teaching (Power Point, Chalk and Talk)
- 14. Assessment Strategy (Bloom's Taxonomy and Rubric based, Quiz, Mid Term, Assignment, Project, Report, Class Test, Presentation, Semester Final): Assignment, Quiz, Mid-Term Exam, End Semester Exam

15. Evaluation Policy (Grading System):

Assessment	Internal	External
Midterm	30%	NA
Continuous Assessment (CA)	30%	NA
End Semester	NA	40%

Continuous Assessments

Sl. No.	Component and Maximum Marks	Weightage	Mode & Duration
1.	Quiz-I (15)	7.5	Online (15 mins)
2.	Quiz -II (15)	7.5	Online (15 mins)
3.	Quiz -III (15)	7.5	Offline (15 mins)
4.	Assignment – I (15)	7.5	Offline

Assignment Rubrics

Assignment Rubrics								
	О	A	В	С	P	F		
Submission	On time and complete	On time and partial	-	-	Late submission	No submission		
Neatness	Very neat with proper labels	Very neat with no proper labels	Neat with labels	Tidy with labels	Tidy with no labels	No submission		
Content	All answers are in detail and sufficient	Some of the answers are not in detail and sufficient	All answers are not in detail and sufficient	-	Incomplete	No submission		

- 16. Make-up Procedures: One Missed Mid-Term Exam, One common quiz for those missed the quiz
- 17. Name & Signature of Course Instructor(s): Dr. Abhishek Raj